

Laboratory	Electronics and Quality Development Centre, B 177/178, G.I.D.C. Electronics Estate, Sector-25, Gandhinagar, Gujarat Location 1: B 177/18, G.I.D.C. Electronics Estate, Sector-25, Gandhinagar, Gujarat Location 2: B/23/2, G.I.D.C. Electronics Estate, Sector-25, Gandhinagar, Gujarat		
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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
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LOCATION: 2

I. EMC TEST FACILITY

1.	Electrical/ Electronic Products And Static Energy Meter	Conducted Emission / Mains Terminal Disturbance Measurement	IS 13779: 1999 Amd. 1-5: 2015 IS 6873 (Part 2/Sec 1): 2012 CISPR 14-1: 2009 IS 6873 (Part 5): 2012 CISPR 15: 2009 CISPR 15: 2013 IS 6873 (Part 3): 2009 CISPR 13: 2001 CISPR 22: 2008 IS 15111-2: 2002 Amd: 6 Sept 2008 CBIP-304: 2008, IS 16101: 2012 Amd. 1 & 2 IS 16102 (Part 2): 2012 Amd. 1 & 2, IS 16103 (Part 2): 2012 Amd. 1 & 2 CISPR11: 2010 CISPR14-1: 2011 CISPR 14-2: 2015 IS 10052 (Part 1): 1999: CISPR 16-1: (1993) BS EN 55011: 2009 Amd. 1: 2010 BSEN 55015: 2013 BS EN 55032: 2015 BS EN 55022: 2010	150 kHz to 30 MHz Upto 200 A/phase 9 kHz to 30 MHz Single Phase: Upto 16 A Three phase: Upto 32 A
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			IEC 61000-6-3: 2010, FCC Part 15 IS 14697: 1999 Amd.1-3: 2004 IEC 62052-11: 2003 IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003 IS 14614: 1998, IEC 61543: 1995 Amd. 1 & 2: 2005, IEC 60255-26: 2013 IEC 62040-2: 2005 BS EN 61800-3: 2004	
2.	Static Energy Meter	Disturbance Power Measurement	CISPR 14-1: 2011 IS 13779: 1999 Amd. 1-5: 2015 IS 14697: 1999 Amd. 1- 3: 2004 CISPR 16-4-2: 2011 Amd. 1: 2014	30 MHz to 300 MHz
3.	Lighting Products (CFL, Electronic Ballast)	Radiated Electromagnetic Disturbances	EN 55015: 2013 CISPR 15: 2013, IS 16102 (Part 2): 2012 Amd. 1 & 2 IS 16101: 2012 Amd. 1 & 2 IS 16103-2: 2012, IS 16103-1: 2012 IS 15111-2: 2002 Amd: 6 Sept 2008	9 kHz to 30 MHz

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4.	Electrical/ Electronic Products And Static Energy meter	Radiated Emission	CISPR11: 2010 CISPR 16-2-3: 2014 IS 6873 (Part 2/Sec I): 2012 CISPR 14-1: 2009 CBIP-304: 2008 BSEN 55011: 2009 Amd. 1: 2010 FCC Part15 BSEN 55032: 2012 IEC 62052-11: 2003 IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003 IS 14614: 1998 IEC 61543: 1995 Amd. 1 & 2: 2005 IEC 60255-26: 2013, IEC 61000-6-3: 2010 ©IEC 62040-2: 2005 BS EN 61800-3: 2004 CISPR 22: 2008, EN 55022: 2010	30 MHz to 1000 MHz
5.	Electrical/ Electronic Products	Radiated Emission	CISPR 16-2-3: 2014 CISPR11: 2010 CISPR 22: 2008 EN 55022: 2010	1 GHz to 6 GHz

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6.	Electrical/ Electronic Products And Static Energy meter	Electrical Fast Transient /Burst Immunity Test	IEC 61000-4-4: 2012 IS 13779: 1999 Amd. 1-5: 2015, IS 14697: 1999 Amd: 3 Oct 2004 IS 14700 (Part 4/Sec IV): 2008, CBIP-304: 2008 IS 6873 (Part 2/Sec II): 2009 CISPR 14-2: 2015 IS 12640 (Part 1): 2008 IS 12640 (Part 2): 2008 IEC 62052-11: 2003 IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003 IS 14614: 1998, CISPR 24: 2015 IEC 60255-22-4: 2008, BSEN 610081: 2012 Amd. 1, IEC 61543: 1995 Amd. 1 & 2: 2005, IEC 61008-1: 2013 Amd. 1 & 2, IEC 61009-1: 2013 Amd. 1 & 2, IEC 60439-1: 2004 Amd. 1, IEC 60204-1: 2009Amd. 1, IEC 61000-6-2: 2005, IEC 61850-3: 2013, BSEN 61000-4-1: 1995, IEC 61000-4-1: 2006 IEC 60947-5-2: 2012	0.25 kV to 4.0 kV 5 kHz & 100 kHz Single Phase: Upto16 A Three phase: Upto 32 A

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			Amd. 1 IEC 60571: 2012 IEC 60601-1-2: 2014 BSEN 61009-1: 2012 Amd. 1 IEC 60947-1: 2014 Amd. 1 & 2 IEC 60947-5-1: 2009 Amd. 1 IEC 61000-6-1: 2005, IEC 61547: 2009 IEC 60255-26: 2013 IEC 61812-1: 2011, IEC 60947-2: 2013 Amd. 1 & 2 IEC 60947-3: 2012 Amd. 1 IEC 60947-4-1: 2012 Amd. 1 IEC 61326-1: 2012 IEC 60335-1: 2013 IEC 61800-3: 2012 IEC 62040-2: 2005,	
7.	Electrical/ Electronic Products And Static Energy meter	Electrostatic Discharge Immunity Test.	IEC 61000-4-2: 2008 IS 13779: 1999 Amd: 4 June 2006 IS 14697: 1999 Amd. 1- 3: 2004 CBIP-304, IEC 61547: 2009 IS 15884: 2010, CISPR 24: 2015 IEC 61036: 1996 Amd. 1: 2000 IEC 62052-11: 2003	Qualitative (2 kV to 30 kV ±30 % at 30 ns ±30 % at 60 ns)

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			IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003, IS 12640 (Part 1): 2000 & IS 12640 (Part 2): 2001, IS 14614: 1998, IEC 1543: 1995 Amnd. 1 & 2 IEC 60255-26: 2013, EN 61008-1: 2004 IEC 61543: 1995 Amd. 1 & 2: 2005 IEC 61008-1: 1999 IEC 60947-2: 2003, IEC 60439-1: 2004 Amd. 1, IEC 60204-1: 2005, IEC 61000-6-2: 2005 CBIP-TR-111: 1997, BS EN 61000-4-1: 1995 IEC 61000-4-1: 2006, IEC 60947-5-2: 2004 incorp Amd. 1 & 2, IEC 60571: 1998, IEC 60601-1-2 : 2001 Amd. 1: 2004, IEC 60694: 2002 Amd. 1 & 2 , EN 61009-1: 1994, IEC 60947-1: 2004 IEC 60947-5-1: 2003, IEC 61326: 2012,	

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			IEC 61000-6-1: 2005-03, IS 15884: 2010 IEC 62040-2: 2005, IEC 61547: 2009	
8.	Electrical/ Electronic Products And Static Energy meter	Radiated, Radio Frequency, Electromagnetic Field Immunity Test	IS 13779: 1999 Amd. 1-5: 2015 IEC 61000-4-3: 2010 IS 14697: 1999 Amd. 3, Oct. 2004 CBIP-304: 2008 IEC 62052-11: 2003 IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003 IS 14614: 1998 , CISPR 24: 2015 IEC 61008-1: 2013 Amd. 1 & 2 IEC 61009-1: 2013 Amd. 1 & 2 IEC 61543: 1995 Amd. 1 & 2 IEC 60947-2: 2013 Amd. 1 & 2, IEC 61326: 2012, IEC 60439-1: 2004 Amd. 1 IEC 60204-1: 2009 Amd. 1 IEC 61000-6-2: 2005 IEC 61850-3: 2013 BSEN 61000-4-1: 1995 IEC 61000-4-1: 2006	Qualitative (80 MHz to 6 GHz 80 MHz to 1 GHz 1 GHz to 6 GHz)

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			IEC 60947-5-2: 2012 Amd. 1 IEC 60571: 2012, IEC 60601-1-2: 2014 BS EN 61009-1: 2012 Amd. 1 IEC 60947-1: 2014 Amd. 1 & 2 IEC 60947-5-1: 2009 Amd. 1 IEC 61000-6-1: 2005 IEC 61547: 2009 IEC 60255-26: 2013 IS 12640 (Part 1): 2008 IS 12640 (Part 2): 2008 IEC 60947-2: 2013 Amd. 1 & 2, IEC 60947-3: 2012 Amd. 1, IEC 60947-4-1: 2012 Amd. 1 IEC 61326-1: 2012 IEC 60335-1: 2013 IEC 61800-3: 2012	
9.	Electrical/ Electronic Products And Static Energymeter	Surge Immunity Test	IEC 61000-4-5 (Edition 3.0): 2014 IEC 60601-1-2: 2014 IS 13779: 1999 Amd. 1-5: 2015 IS 14697: 1999Amd.1- 3: 2004 ITU K.20, ITU K.41/K.44, IEC 62052-11: 2003 IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003 IEC 60255-22-5: 2008, CISPR 24: 2015 IEC 61000-4-1: 2006 IEC 61547: 2009 IEC 61000-4-1: 2006	Qualitative (0.5 kV to 6.0 kV Single Phase: Upto 16 A Three phase: Upto 32 A)

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			IEC 61547: 2009 EN 61008-1: 2013 Amd. 1 & 2 IEC 61543: 1995 Amd. 1 & 2 IEC 60947-2: 2013 Amd. 1 & 2 IEC 60439-1: 2004 Amd. 1, IEC 60204-1: 2009Amd. 1, IEC 61000-6-2: 2005, IEC 61850-3: 2013, BS EN 61000-4-1: 1995 IEC 61000-4-1: 2006 IEC 60947-5-2: 2012 Amd. 1 IEC 60571: 2012, IEC 60601-1-2: 2014 IEC 60947-1: 2014 Amd. 1 & 2 IEC 60947-5-1: 2009 Amd. 1 IEC 61000-6-1: 2005 IEC 60255-26: 2013, IEC 61812-1: 2011 IS 12640 (Part 1): 2008 IS 12640 (Part 2): 2008 IEC 61008-1: 2013 Amd. 1 & 2 IEC 61009-1: 2013 Amd. 1 & 2 BS EN 55024: 2010 IEC 60947 -2: 2013 Amd. 1 & 2 IEC 60947-3: 2012 Amd. 1 IEC 60947-4-1: 2012 Amd. 1 IEC 61326-1: 2012 IEC 60335-1: 2013 IEC 61800-3: 2012, IEC 60065: 2005, IEC 62040-2: 2005	

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10.	Electrical/ Electronic Products And Static Energymeter	Immunity To Conducted Disturbances Induced By RF Fields	IEC 61000-4-6: 2013 IEC 62052-11: 2003 IEC 62053-21: 2004 IEC 62053-22: 2003 IEC 62053-23: 2003, IS 14614: 1998, IEC 1543 (1995) Amd. 1 & 2 CBIP-304: 2008, IEC 60255-26: 2013 EN 61008-1: 2013 Amd. 1 & 2 IEC 61543: 1995 Amd. 1 & 2 IEC 60947-2: 2013 Amd. 1 & 2 IEC 60439-1: 2004 Amd. 1, IEC 60204-1: 2009Amd. 1, IEC 61000-6-2: 2005, IEC 61850-3: 2013, BS EN 61000-4-1: 1995 IEC 61000-4-1: 2006 IEC 60571: 2012 IEC 60601-1-2: 2014 IEC 60947-1: 2014 Amd. 1 & 2 IEC 60947-5-1: 2009 Amd. 1 IEC 61000-6-1: 2005 IEC 61547: 2009, CISPR 24: 2015 IEC 60255-26: 2013 IEC 61812-1: 2011 IS 12640 (Part 1): 2008 IS 12640 (Part 2): 2008 IEC 61008-1: 2013 Amd. 1 & 2 IEC 61009-1: 2013 Amd. 1 & 2 IEC 60947-2: 2013 Amd. 1 & 2	Qualitative (1 V to 10 V Upto 100 A 150 kHz to 80 MHz)

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			IEC 60947-3: 2012 Amd. 1 IEC 60947-4-1: 2012 Amd. 1 IEC 61326-1: 2012 IEC 60335-1: 2013, IEC 61800-3: 2012, IEC 62040-2: 2005	
11.	Electrical/ Electronic Products And Static Energymeter	Ring Wave Immunity Test	IEC 61000-4-12: 2006 IEC 60255-26: 2013 IS 12640 (Part 1): 2008 IS 12640 (Part 2): 2008 IEC 61008-1: 2012 Amd. 1 & 2 IEC 61009-1: 2013 Amd. 1 & 2 IEC 62052-11: 2003, IEC 62053-22: 2003, IEC 62053-23: 2003	Qualitative
		Voltage Dips & Interruptions	IEC 61000-4-11: 2004 IS 14614: 1998, IEC 1543 (1995) Amd. 1 & 2, IEC61547: 2009 IEC 62052-11: 2003, IEC 62053-21: 2004, IEC 62053-22: 2003, IEC 62053-23: 2003 IEC 60255-26: 2013	Qualitative (Upto 260 V Upto 16 A/ phase)

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12.	Electrical/ Electronic Products	Power Frequency Magnetic Field Immunity Test	IEC 61000-4-8: 2009 IEC 60255-26: 2013 IEC 61812-1: 2011 BS EN 55024: 2010 IEC 60947-1: 2014 Amd. 1 IEC 60947-2: 2013 Amd. 1 IEC 61326-1: 2012, EN 50121-4: 2006 CISPR 24: 2015, IEC 61547: 2009	Qualitative
		Impulse Magnetic Field Immunity Test	IEC 61000-4-9: 2016	Qualitative

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